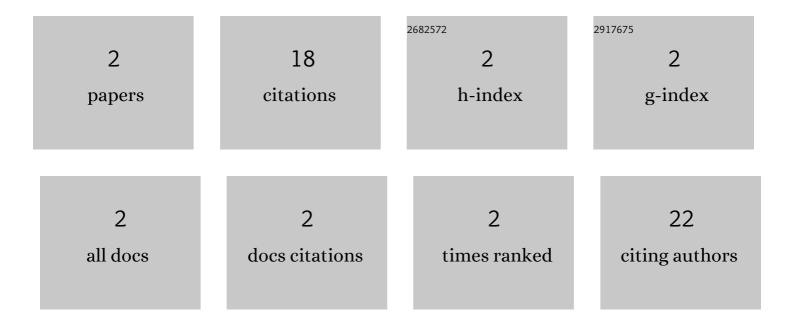
Mohamed Labed

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/4510961/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	Simulation of the influence of the gate dielectric on amorphous indium-gallium-zinc oxide thin-film transistor reliability. Journal of Computational Electronics, 2019, 18, 509-518.	2.5	11
2	Numerical Simulation on Thickness Dependency and Bias Stress Test of Ultrathin IGZO Thinâ€Film Transistors Via a Solution Process. Physica Status Solidi (A) Applications and Materials Science, 2019, 216, 1800987.	1.8	7

2